Special Issue

Terahertz Applications for Nondestructive Testing

Message from the Guest Editor

Terahertz technologies have reached a level of maturity where they are being increasing adopted for industrial deployment. Nondestructive testing, condition monitoring, and quality control are the primary areas of industrial terahertz applications. This Special Issue on "Terahertz Applications for Nondestructive Testing" is organised in association with the Terahertz Users Group run by the British Institute of Non-Destructive Testing (BINDT) and the International Committee on Non-Destructive Testing (ICNDT). It is an opportunity for providers and developers of THz instrumentation to showcase their technologies to the user community. Equally, it is an opportunity for THz users to bring their needs and challenges to the attention of technology providers.

Guest Editor

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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